

Notice of References Cited	Application/Control No. 10/582,330	Applicant(s)/Patent Under Reexamination SUMIYA, HITOSHI	
	Examiner SHENG HAN	Art Unit 1793	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0110024	05-2005	Swain et al.	257/077
	B	US-			
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	L	US-			
	M	US-			

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